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**INFORMATION DISCLOSURE
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Complete if Known

Application Number	09/869,789
Filing Date	July 23, 2002
First Named Inventor	Hans-Ulrich Krottil et al.
Art Unit	2856
Examiner Name	Noland, Thomas
Attorney Docket Number	TIL0004

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
[Signature]		US- 5,444,244	08/22/1995	Kirk et al.	<div>RECEIVED NOV 11 2003 MAIL ROOM</div>
		US- 5,503,010	04/02/1996	Yamanaka	
		US- 5,519,212	05/21/1996	Elings et al.	
		US- 5,763,768	06/09/1998	Henderson et al.	
		US- 5,804,708	09/08/1998	Yamanaka et al.	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
[Signature]		EP 0 896 201 A1	02-10-1999	Muramatsu et al.	<div>RECEIVED NOV 11 2003 MAIL ROOM</div>	
		WO 00/40946	07-13-2000	Stifter et al.		

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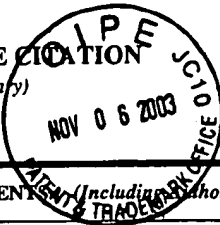
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Docket Number (Optional)

TIL0004

Application Number

09/869,789

Applicant(s)

Hans-Ulrich Krottil et al.

Filing Date

July 23, 2002

Group Art Unit

2856

*EXAMINER
INITIAL

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

T. Goddenhenrich et al., "A lateral modulation technique for simultaneous friction and topography measurements with the atomic force microscope", Rev. Sci. Instrum. 65 (9), September 1994, pp. 2870-2873.

S. Watanabe et al., "Two-directional dynamic mode force microscopy: Detection of directional force gradient", J. Vac. Sci. Technol. B 12(3), May/June 1994, pp. 1577-1580.

Kazushi Yamanaka et al., "Ultrasonic force microscopy for nanometer resolution subsurface imaging", Appl. Phys. Lett. 64 (2), 10 January 1994, pp. 178-180.

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